## Notice of References Cited Application/Control No. 10/073,923 Examiner Bob A. Phunkulh Applicant(s)/Patent Under Reexamination MUKAI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,980,519	12-2005	Horn et al.	370/235
*	В	US-6,804,256	10-2004	Chang, Tsung-Shien	370/468
*	С	US-6,775,701	08-2004	Pan et al.	709/226
*	D	US-6,434,164	08-2002	Matsunaga et al.	370/443
*	E	US-2004/0202174	10-2004	Kim et al.	370/395.1
*	F	US-2003/0039211	02-2003	Hvostov et al.	370/230
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			·
	К	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	P.					
	α					
	R					
	S					
	Т			-2 124 dis-1.6-2 - 2 4		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	v		
	w		
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.